54ACT16241, 74ACT16241 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

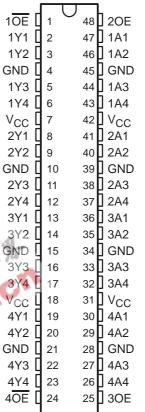
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- Members of the Texas Instruments Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines or Buffer Memory Address Registers
- Flow-Through Architecture Optimizes
 PCB Layout
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Pin Spacings

description

The 'ACT16241 are 16-bit buffers or line drivers designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. The devices can be used as four 4-bit buffers, two 8-bit buffers, or one 16-bit buffer. These devices provide true outputs and complementary output-enable (OE and \overline{OE}) inputs.

54ACT16241 . . . WD PACKAGE 74ACT16241 . . . DL PACKAGE (TOP VIEW)



The 74ACT16241 is packaged in TI's shrink small-outline package, which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16241 is characterized for operation over the full military temperature range of –55°C to 125°C. The 74ACT16241 is characterized for operation from –40°C to 85°C.



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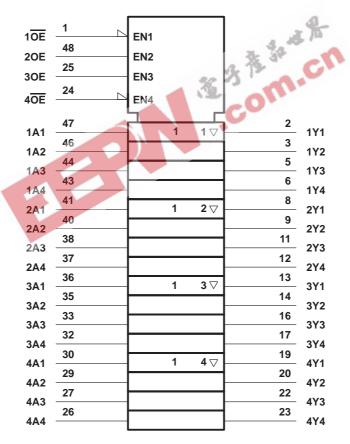
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FUNCTION TABLES

INP	JTS	OUTPUT
OE	Α	Υ
L	Н	Н
L	L	L
Н	Χ	Z

INP	UTS	OUTPUT
OE	Α	Υ
Н	Н	Н
Н	L	L
L	X	Z

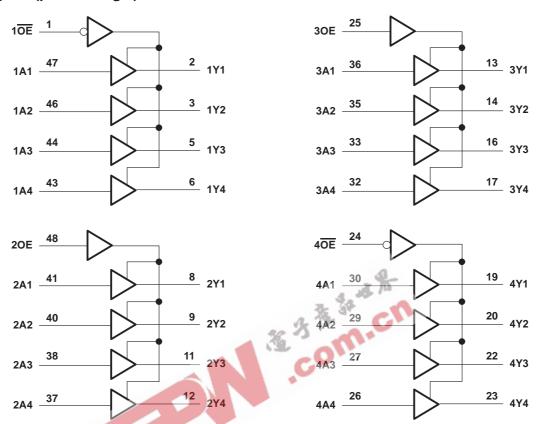
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	
Input voltage range, V _I (see Note 1)	
Output voltage range, VO (see Note 1)	
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	
Continuous current through V _{CC} or GND	±400 mA
Maximum package power dissipation at $T_A = 55^{\circ}$ C (in still air) (see	Note 2): DL package 1.2 W
Storage temperature range, T _{stg}	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The maximum package power dissipation is calculated using a junction temperature of 150 °C and a board trace length of 750 mils.



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recommended operating conditions (see Note 3)

		54ACT16241			74ACT16241			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNII
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		2	2			V
V _{IL}	Low-level input voltage		Š	0.8			0.8	V
VI	Input voltage	0	72/2	VCC	0		Vcc	V
٧o	Output voltage	0	7	VCC	0		VCC	V
ІОН	High-level output current		2	-24			-24	mA
loL	Low-level output current		5	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	T _A = 25°C	54ACT16241	74ACT16241	UNIT
PARAMETER	TEST CONDITIONS	vcc -	MIN TYP MAX	MIN MAX	MIN MAX	UNIT
	I _{OH} = -50 μA	4.5 V	4.4	4.4	4.4	
	ΙΟΗ = -30 μΑ	5.5 V	5.4	5.4	5.4	
VOH	04.554	4.5 V	3.94	3.8	3.8	V
	I _{OH} = -24 mA	5.5 V	4.94	4.8	4.8	
	I _{OH} = -75 mA [†]	5.5 V		3.85	3.85	
	le: - 50 uA	4.5 V	0.1	0.1	0.1	
	ΙΟL = 50 μΑ	5.5 V	0.1	0.1	0.1	
V _{OL}	les = 24 mA	4.5 V	0.36	0.44	0.44	V
	I _{OL} = 24 mA	5.5 V	0.36	0.44	0.44	
	I _{OL} = 75 mA [†]	5.5 V		1.65	1.65	
lį	V _I = V _{CC} or GND	5.5 V	±0.1	±1	±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V	±0.5	±5	±5	μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	8	80	80	μΑ
ΔI _{CC} ‡	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V	0.9	1	1	mA
C _i	V _I = V _{CC} or GND	5 V	4.5			pF
Co	$V_O = V_{CC}$ or GND	5 V	13			pF

[†]Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

[‡] This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM TO (INPUT)	T _A = 25°C		54ACT16241		74ACT16241		UNIT			
PARAMETER		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT		
t _{PLH}	А	Y	3.3	6.5	8.4	3.3	9.5	3.3	9.5	20	
t _{PHL}			2.3	6.3	8.2	2.3	9.1	2.3	9.1	ns	
^t PZH			2.3	6.5	8.3	2.3	9.4	2.3	9.4	200	
t _{PZL}	OE or OE	ī	2.9	7.3	9.3	2.9	10.5	2.9	10.5	ns	
^t PHZ	OE or OE	<u> </u>	V	4.3	8.9	10.6	4.3	11.6	4.3	11.6	20
^t PLZ		r	4	8.1	9.8	4	10.7	4	10.7	ns	

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CO	TYP	UNIT	
C _{pd} Power dissipation capacitance	Outputs enabled	$C_1 = 50 \text{ pF}, \qquad f = 1 \text{ MH}$		43	nE
	Outputs disabled	CL = 50 pr,	f = 1 MHz	10	pF

PARAMETER MEASUREMENT INFORMATION **TEST** S1 tPLH/tPHL Open **500** Ω From Output $\textbf{2} \times \textbf{V}_{\textbf{CC}}$ tPLZ/tPZL **Under Test** GND tPHZ/tPZH $C_L = 50 pF$ 500Ω (see Note A) Output 3 V LOAD CIRCUIT Control 1.5 V 1.5 V (low-level enabling) ^tPZL tPLZ -Input Output ≈ VCC 1.5 V 50% V_CC Waveform 1 20% V_CC S1 at $2 \times V_{CC}$ v_{OL} (see Note B) ^tPLH tPHZ → Output Vон ۷он 80% V_CC Waveform 2 50% V_{CC} 50% V_{CC} 50% V_CC Output S1 at GND VOL ≈ 0 V (see Note B) **VOLTAGE WAVEFORMS VOLTAGE WAVEFORMS**

NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- $\label{eq:defD} \textbf{D.} \quad \text{The outputs are measured one at a time with one input transition per measurement.}$

Figure 1. Load Circuit and Voltage Waveforms



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